

*OK to enter 7/17/06 JBR*

**AMENDMENTS TO THE ABSTRACT**

**Please amend the originally filed Abstract with the following paragraph:**

A method for testing an CMOS ternary content addressable memory (TCAM) device includes a match line test to identify stuck match lines, a pull down test to identify weak pull downs (from the match line to ground), and a row-by-row match test. During the row-by-row match test a failed cell can be repaired or the row associated with the failed cell can be disabled. A failed cell or its associated row can also be ~~repair~~ repaired or disabled, respectively, after the test. Additionally, individual CAM cells which are identified as being defective can be further tested to identify which component of the CAM cell failed.